



SLOVENSKI STANDARD SIST EN 60689:2009

01-maj-2009

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Measurement and test methods for tuning fork quartz crystal units in the range from 10 kHz to 200 kHz and standard values (IEC 60689:2008)

Mess- und Prüfverfahren für Stimmgabelquarze im Frequenzbereich von 10 kHz bis 200 kHz sowie Richtwerte (IEC 60689:2008)

Méthodes de mesure et d'essai concernant le réglage des résonateurs à quartz dans la plage comprise entre 10 kHz et 200 kHz et valeurs normales (CEI 60689:2008)

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Ta slovenski standard je istoveten z: EN 60689:2009

ICS:

31.140 Úa: [^|\ dã } ^Á
åã | ^|\ dã } ^Á æ | æ ^ Piezoelectric and dielectric devices

SIST EN 60689:2009

en

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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN 60689

March 2009

ICS 31.140

English version

**Measurement and test methods for tuning fork quartz crystal units
in the range from 10 kHz to 200 kHz and standard values
(IEC 60689:2008)**

Méthodes de mesure et
d'essai concernant le réglage
des résonateurs à quartz
dans la plage comprise entre
10 kHz et 200 kHz et valeurs normales
(CEI 60689:2008)

Mess- und Prüfverfahren
für Stimmgabelquarze
im Frequenzbereich
von 10 kHz bis 200 kHz
sowie Richtwerte
(IEC 60689:2008)

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This European Standard was approved by CENELEC on 2009-03-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: avenue Marnix 17, B - 1000 Brussels

Foreword

The text of document 48/809/FDIS, future edition 2 of IEC 60689, prepared by IEC TC 49, Piezoelectric and dielectric devices for frequency control and selection, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60689 on 2009-03-01.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2009-12-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2012-03-01

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 60689:2008 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60068-1	NOTE Harmonized as EN 60668-1:1994 (not modified).
IEC 60068-2-1	NOTE Harmonized as EN 60668-2-1:2007 (not modified).
IEC 60068-2-2	NOTE Harmonized as EN 60668-2-2:2007 (not modified).
IEC 60068-2-7	NOTE Harmonized as EN 60668-2-7:1993 (not modified).
IEC 60068-2-13	NOTE Harmonized as EN 60668-2-13:1999 (not modified).
IEC 60068-2-14	NOTE Harmonized as EN 60668-2-14:1999 (not modified).
IEC 60068-2-17	NOTE Harmonized as EN 60668-2-17:1994 (not modified).
IEC 60068-2-20	NOTE Harmonized as EN 60668-2-20:2008 (not modified).
IEC 60068-2-21	NOTE Harmonized as EN 60668-2-21:2006 (not modified).
IEC 60068-2-27	NOTE Harmonized as EN 60668-2-27:1993 (not modified).
IEC 60068-2-30	NOTE Harmonized as EN 60668-2-30:2005 (not modified).
IEC 60068-2-31	NOTE Harmonized as EN 60668-2-31:2008 (not modified).
IEC 60068-2-45	NOTE Harmonized as EN 60668-2-45:1992 (not modified).
IEC 60068-2-78	NOTE Harmonized as EN 60668-2-78:2001 (not modified).

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60027	Series	Letter symbols to be used in electrical technology	EN 60027	Series
IEC 60050-561	- ¹⁾	International Electrotechnical Vocabulary (IEV) - Chapter 561: Piezoelectric devices for frequency control and selection	-	-
IEC 60122-1	- ¹⁾	Quartz crystal units of assessed quality - Part 1: Generic specification	EN 60122-1	2002 ²⁾
IEC 60122-3	- ¹⁾	Quartz crystal units of assessed quality - Part 3: Standard outlines and lead connections	EN 60122-3	2001 ²⁾
IEC 60444	Series	Measurement of quartz crystal unit parameters by zero phase technique in a pi-network	EN 60444	Series
IEC 60617	Data-base	Graphical symbols for diagrams	-	-
ISO 1000	1992	SI units and recommendations for the use of their multiples and of certain other units	-	-

¹⁾ Undated reference.

²⁾ Valid edition at date of issue.

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INTERNATIONAL STANDARD

**Measurement and test methods for tuning fork quartz crystal units in the range
from 10 kHz to 200 kHz and standard values**

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ad48993fe4cd/sist-en-60689-2009](https://standards.iteh.ai/catalog/standards/sist/2b1be3a5-94ac-4d62-a3d1-ad48993fe4cd/sist-en-60689-2009)

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CONTENTS

FOREWORD.....	4
1 Scope.....	6
2 Normative references	6
3 Overview	6
3.1 General.....	6
3.2 Applied frequency range.....	6
3.3 Measurement method.....	6
3.4 Load capacitance	7
3.5 Recommended drive level	7
3.6 Measurement conditions.....	7
3.7 Measurement of frequency-temperature characteristics.....	7
3.8 Load capacitance frequency characteristics	7
4 Measurement methods	7
4.1 Method A.....	7
4.1.1 Vector network analyzer/vector impedance analyzer.....	7
4.1.2 Block diagram.....	7
4.1.3 Specifications for vector network analyzer/vector impedance analyzer	8
4.1.4 Test fixture.....	8
4.1.5 Measurement of equivalent circuit constants	9
4.1.6 Frequency pulling	10
4.2 Method B.....	10
4.2.1 General	10
4.2.2 Block diagram.....	10
4.2.3 Calibration.....	11
4.2.4 Procedure.....	12
5 Measurement conditions.....	12
5.1 General.....	12
5.2 Measurement conditions.....	12
5.3 Measurement of the frequency-temperature dependence	13
5.3.1 General	13
5.3.2 Block diagram.....	13
5.3.3 Determination of the turnover point and parabolic coefficient β (standard reference method)	14
5.3.4 Measurement of the frequency versus temperature characteristics (mass production method)	14
5.3.5 Frequency C_L curve.....	15
6 Test and environmental examination	15
6.1 Application of the definition of IEC 60122-1.....	15
6.2 Magnetism – Influence of a magnetic field on the frequency.....	16
6.3 Enclosure.....	16
6.4 Measuring conditions and electric performance	16
6.4.1 General	16
6.4.2 Measurement conditions.....	16
6.4.3 Standard values	16
Bibliography.....	18

Figure 1 – Block diagram of the measurement method using the vector network analyzer or vector impedance analyzer	8
Figure 2 – Block diagram of test fixture	9
Figure 3 – Block diagram of test fixture (including a load capacitance).....	9
Figure 4 – Block diagram of test fixture for bridge method	11
Figure 5 – Block diagram of test fixture for bridge method (including a load capacitance)	11
Figure 6 – Block diagram of measurement of the frequency-temperature dependence	13
Figure 7 – Frequency–temperature template (Turnover point: $25 \pm 5 \text{ }^\circ\text{C}$, $\beta = -45 \times 10_{-9}/^\circ\text{C}_2$)	14
Figure 8a) – $\Delta f/f$ versus C_L curve	15
Figure 8b) – $\Delta f/f$ versus C_L curve	15
Figure 8 – $\Delta f/f$ versus C_L curve with different C_{Ls}	15
Table 1 – Specifications for vector network analyzer/vector impedance analyzer	8
Table 2 – Standard values	17

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**MEASUREMENT AND TEST METHODS FOR TUNING FORK
QUARTZ CRYSTAL UNITS IN THE RANGE FROM 10 kHz TO 200 kHz
AND STANDARD VALUES**

FOREWORD

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International Standard IEC 60689 has been prepared by IEC technical committee 49: Piezoelectric and dielectric devices for frequency control and selection.

This second edition cancels and replaces the first edition published in 1980. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) The title of the first edition is *Measurements and test methods for 32 kHz quartz crystal units for wrist watches and standard values*. The title is modified and the frequency range of this second edition is extended to the range from 10 kHz to 200 kHz.
- b) The Lissajous method is defined in the first edition as the standard measurement method. The PI network and bridge method are used in this second edition.
- c) The PI network has a transformer for impedance matching. This composition differs from that of IEC 60444-1.

The text of this standard is based on the following documents:

FDIS	Report on voting
49/809/FDIS	49/815/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition; or
- amended.

A bilingual version of this publication may be issued at a later date.

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